

**Notice of References Cited**

Application/Control No.

10/080,848

Applicant(s)/Patent Under  
Reexamination  
OHTAKE ET AL.

Examiner

DuyVu n Deo

Art Unit

1765

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0162407	08-2003	Maex et al.	438/725
	B	US-6,395,632	05-2002	Farrar, Paul A.	438/687
	C	US-6,207,576	03-2001	Wang et al.	438/706
	D	US-6,235,628	05-2001	Wang et al.	438/638
	E	US-6,284,149	09-2001	Li et al.	216/64
	F	US-6,265,780	07-2001	Yew et al.	257/759
	G	US-6,383,931	05-2002	Flanner et al.	438/689
	H	US-6,417,112	07-2002	Peyne et al.	438/754
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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